

IDS 4/12/04

Sheet 1 of 1

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 107317-00064	SERIAL NO. New Appln.
LIST OF REFERENCES CITED BY APPLICANT  (Use several sheets if necessary)		APPLICANT Kenji MARUYAMA et al	10/821 841
		FILING DATE April 12, 2004	GROUP 2812

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
94	AA	5,995,359	11/30/99	KLEE et al			
94	AB	6,258,459 B1	7/10/01	NOGUCHI et al			
	AC						
	AD						
	AE						
	AF						

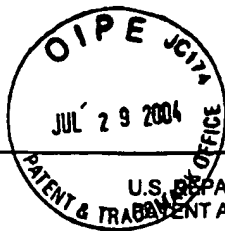
## FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION		
							YES	NO	PART.
94	AG	10-189887	7/21/98	Japan			XX		
	AH								
	AI								
	AJ								
	AK								
	AL								

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AM	
	AN	
	AO	

EXAMINER <i>Jennifer M. Kennedy</i>	DATE CONSIDERED <i>March 22 2005</i>
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	



Sheet 1 of 1

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

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10/821,841

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(Use several sheets if necessary)

APPLICANT

MARUYAMA, et al.

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## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
JM	AA	5,182,723	March 9, 1993	Fujiu et al.			
JM	AB	6,194,753 B1	February 27, 2001	Seon et al.			
JM	AC	2001/0005026 A1	June 28, 2001	Nakamura			
JM	AD	5,514,484	May 7, 1996	Nashimoto			
JM	AE	5,623,439	April 22, 1997	Gotoh et al.			
	AF						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO PART.		
JM	AG	EP 0 957 516 A1	March 24, 1997	Europe					
JM	AH	EP 0795 898 A2	March 10, 1997	Europe					
	AI								
	AJ								
	AK								
	AL								

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

JM	AM	P.C. Van Buskirk et al., "Common and Unique Aspects of Perovskite Thin Film CVD Processes" Integrated Ferroelectrics, Vol. 21, pgs. 273-289, (1998).
	AN	
	AO	

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Quinn M. Kennedy

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